



## DUAL ENHANCEMENT MODE (N-CHANNEL / P-CHANNEL)

### DESCRIPTION

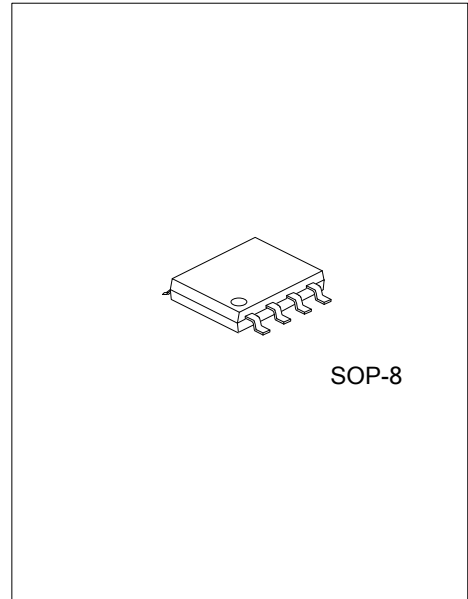
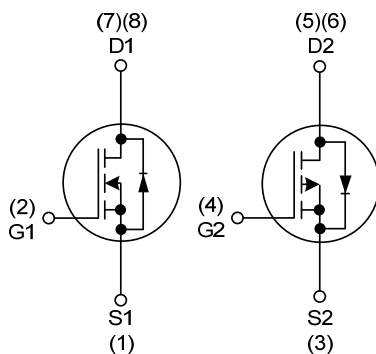
The UTC **F17NP055** incorporates a N-channel MOSFET and a P-channel MOSFET enhancement mode silicon gate power MOSFET with Fast Body Diode. is designed high voltage, high speed power switching applications such, is designed to have better characteristics. such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics.

This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient AC to DC converters and bridge circuits.

### FEATURES

- \* N-CHANNEL: 55V/17A  
 $R_{DS(on)} \leq 44 \text{ m}\Omega @ V_{GS}=10V, I_D=8.5A$
- \* P-CHANNEL: -55V/-17A  
 $R_{DS(on)} \leq 134 \text{ m}\Omega @ V_{GS}=-10V, I_D=-8.5A$
- \* Fast body diode MOSFET technology
- \* High switching speed

### SYMBOL



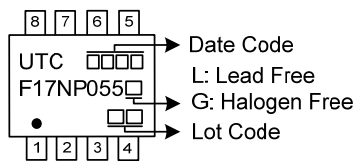
### ■ ORDERING INFORMATION

Ordering Number		Package	Pin Assignment								Packing
Lead Free	Halogen Free		1	2	3	4	5	6	7	8	
F17NP055L-S08-R	F17NP055G-S08-R	SOP-8	S1	G1	S2	G2	D2	D2	D1	D1	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source

<p>F17NP055G-S08-R</p>	<p>(1) R: Tape Reel</p> <p>(2) S08: SOP-8</p> <p>(3) G: Halogen Free and Lead Free, L: Lead Free</p>
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### ■ MARKING



■ ABSOLUTE MAXIMUM RATINGS ( $T_C=25^\circ\text{C}$ , unless otherwise specified)

PARAMETER	SYMBOL	RATINGS		UNIT	
		N-CHANNEL	P-CHANNEL		
Drain-Source Voltage	$V_{DSS}$	55	-55	V	
Gate-Source Voltage	$V_{GSS}$	$\pm 20$	$\pm 20$	V	
Drain Current	Continuous	$I_D$	17	-17	A
	Pulsed (Note 1)	$I_{DM}$	34	-34	A
Avalanche Energy, Single Pulse (Note 3)	$E_{AS}$	73	63	mJ	
Power Dissipation	$P_D$	1.9		W	
Junction Temperature	$T_J$	-55 ~ +150		$^\circ\text{C}$	
Storage Temperature Range	$T_{STG}$	-55 ~ +150		$^\circ\text{C}$	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating : Pulse width limited by maximum junction temperature.

3. N-Channel:  $L=0.1\text{mH}$ ,  $I_{AS}=38.2\text{A}$ ,  $V_{DD}=30\text{V}$ ,  $R_G=25\Omega$ , Starting  $T_J=25^\circ\text{C}$

P-Channel:  $L=0.1\text{mH}$ ,  $I_{AS}=-35.7\text{A}$ ,  $V_{DD}=-30\text{V}$ ,  $R_G=25\Omega$ , Starting  $T_J=25^\circ\text{C}$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	$\theta_{JA}$	90	$^\circ\text{C}/\text{W}$
Junction to Case	$\theta_{JC}$	65.7	$^\circ\text{C}/\text{W}$

Note: Device mounted on FR-4 substrate  $P_c$  board, 2oz copper, with 1inch square copper plate.

■ ELECTRICAL CHARACTERISTICS ( $T_J=25^\circ\text{C}$ , unless otherwise specified)

**N-Channel**

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
<b>OFF CHARACTERISTICS</b>							
Drain-Source Breakdown Voltage	$BV_{DSS}$	$I_D=250\mu\text{A}$ , $V_{GS}=0\text{V}$	55			V	
Drain-Source Leakage Current	$I_{DSS}$	$V_{DS}=55\text{V}$ , $V_{GS}=0\text{V}$			1	$\mu\text{A}$	
Gate-Source Leakage Current	$I_{GSS}$	Forward			+100	nA	
		Reverse			-100	nA	
<b>ON CHARACTERISTICS</b>							
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}$ , $I_D=250\mu\text{A}$	2.0		4.0	V	
Static Drain-Source On-State Resistance (Note 2)	$R_{DS(ON)}$	$V_{GS}=10\text{V}$ , $I_D=8.5\text{A}$			44	m $\Omega$	
<b>DYNAMIC PARAMETERS</b>							
Input Capacitance	$C_{ISS}$	$V_{GS}=0\text{V}$ , $V_{DS}=25\text{V}$ , $f=1.0\text{MHz}$		702		pF	
Output Capacitance	$C_{OSS}$				171		pF
Reverse Transfer Capacitance	$C_{RSS}$				31		pF
<b>SWITCHING PARAMETERS</b>							
Total Gate Charge (Note 2)	$Q_G$	$V_{DS}=44\text{V}$ , $V_{GS}=10\text{V}$ , $I_D=17\text{A}$ , $I_G=1\text{mA}$ (Note 1, 2)		25		nC	
Gate to Source Charge	$Q_{GS}$			5		nC	
Gate to Drain Charge	$Q_{GD}$			8		nC	
Turn-ON Delay Time (Note 2)	$t_{D(ON)}$	$V_{DS}=27.5\text{V}$ , $V_{GS}=10\text{V}$ , $I_D=17\text{A}$ , $R_G=6\Omega$ (Note 1, 2)		6		ns	
Rise Time	$t_R$			17		ns	
Turn-OFF Delay Time	$t_{D(OFF)}$			30		ns	
Fall-Time	$t_F$			17		ns	
<b>SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS</b>							
Drain-Source Diode Forward Voltage(Note 2)	$V_{SD}$	$I_S=17\text{A}$ , $V_{GS}=0\text{V}$			1.4	V	

■ ELECTRICAL CHARACTERISTICS (Cont.)

**P-Channel**

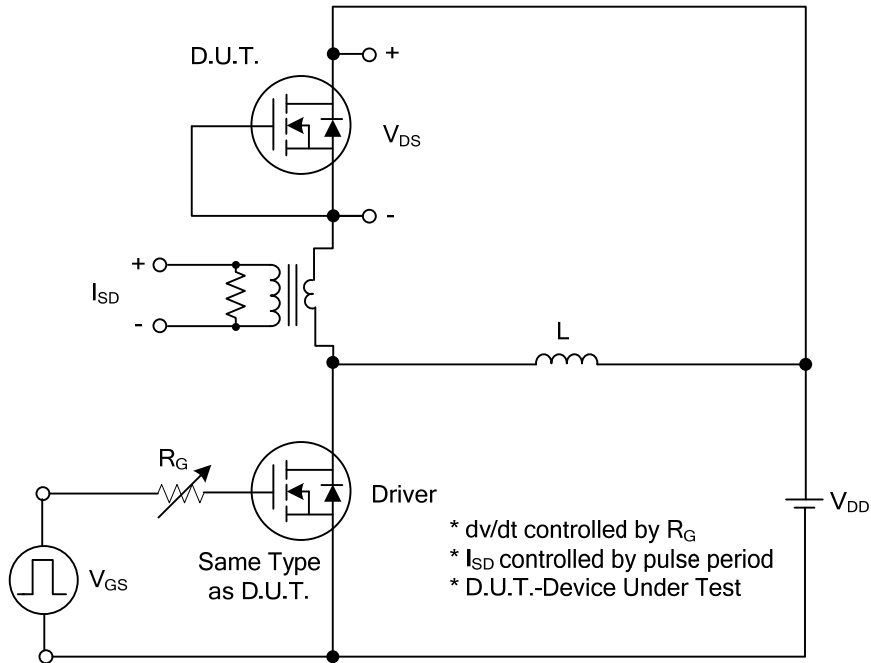
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$I_D = -250\mu A, V_{GS} = 0V$	-55			V
Drain-Source Leakage Current	$I_{DSS}$	$V_{DS} = -55V, V_{GS} = 0V$			-1	$\mu A$
Gate-Source Leakage Current	Forward	$I_{GSS}$			+100	nA
	Reverse					
		$V_{GS} = -20V$			-100	nA
<b>ON CHARACTERISTICS</b>						
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_D = -250\mu A$	-2.0		-4.0	V
Static Drain-Source On-State Resistance (Note 2)	$R_{DS(ON)}$	$V_{GS} = -10V, I_D = -8.5A$			134	m $\Omega$
<b>DYNAMIC PARAMETERS</b>						
Input Capacitance	$C_{ISS}$	$V_{GS} = 0V, V_{DS} = -25V,$ $f = 1.0MHz$		638		pF
Output Capacitance	$C_{OSS}$			178		pF
Reverse Transfer Capacitance	$C_{RSS}$			40		pF
<b>SWITCHING PARAMETERS</b>						
Total Gate Charge (Note 2)	$Q_G$	$V_{DS} = -44V, V_{GS} = -10V,$ $I_D = -17A, I_G = -1mA$ (Note 1, 2)		19		nC
Gate to Source Charge	$Q_{GS}$			7		nC
Gate to Drain Charge	$Q_{GD}$			6		nC
Turn-ON Delay Time (Note 2)	$t_{D(ON)}$	$V_{DS} = -27.5V, V_{GS} = -10V,$ $I_D = -17A, R_G = 6\Omega$ (Note 1, 2)		11		ns
Rise Time	$t_R$			17		ns
Turn-OFF Delay Time	$t_{D(OFF)}$			22		ns
Fall-Time	$t_F$			17		ns
<b>SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS</b>						
Drain-Source Diode Forward Voltage(Note 2)	$V_{SD}$	$I_S = -17A, V_{GS} = 0V$			-2.0	V

Notes: 1. Pulse width limited by maximum junction temperature

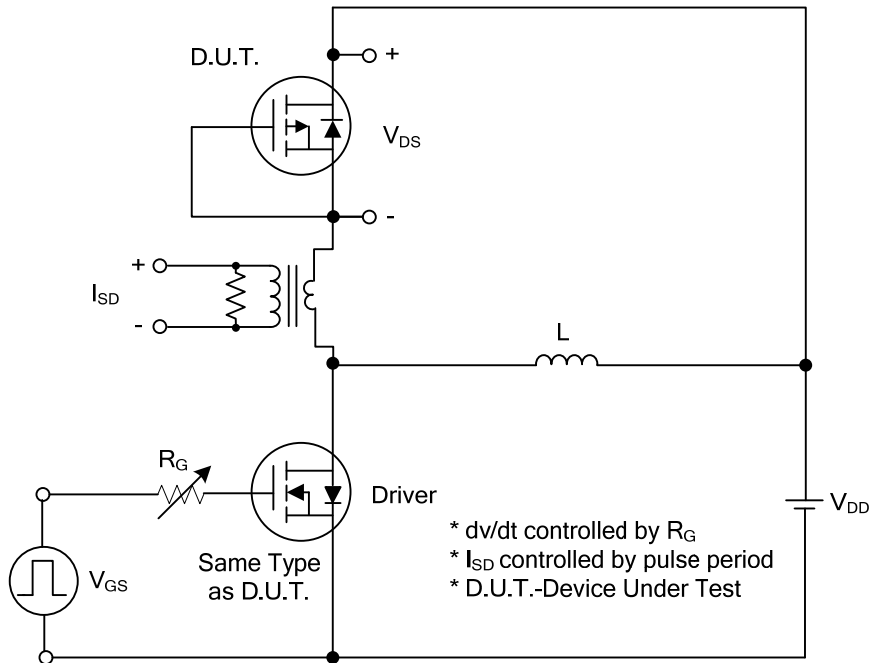
2. Pulse width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$

TEST CIRCUITS AND WAVEFORMS

N-CHANNEL

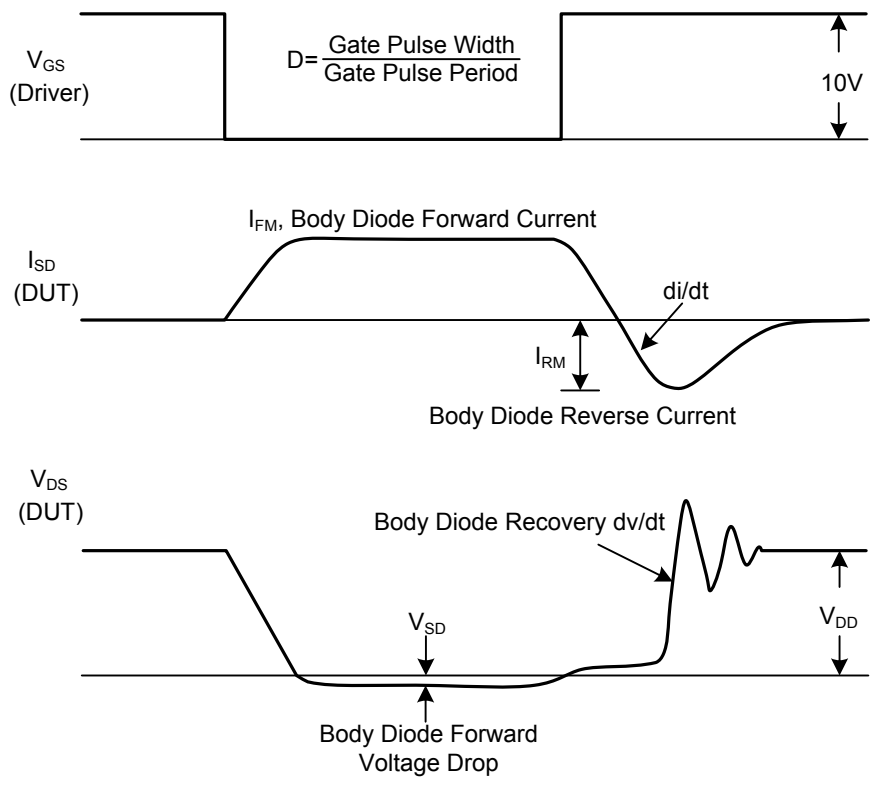


P-CHANNEL



Peak Diode Recovery  $dv/dt$  Test Circuit

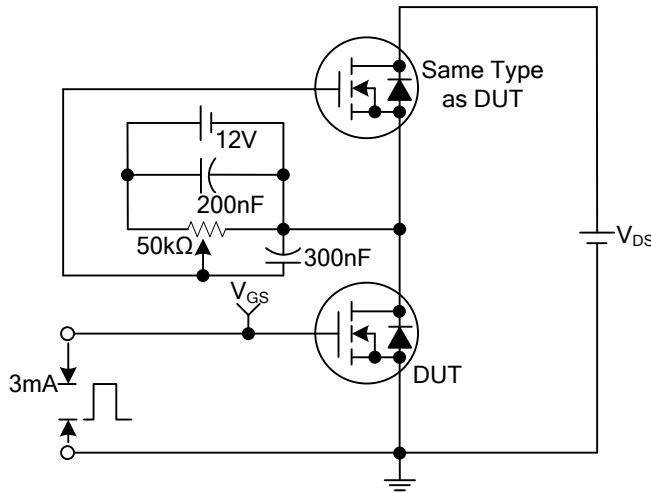
■ TEST CIRCUITS AND WAVEFORMS



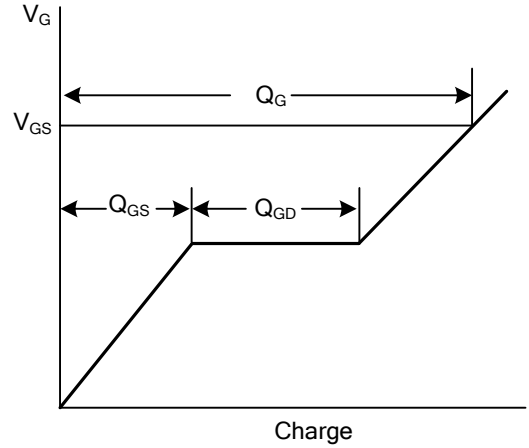
Peak Diode Recovery  $dv/dt$  Waveforms

TEST CIRCUITS AND WAVEFORMS

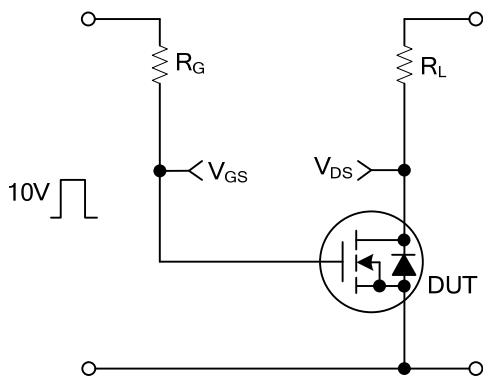
N-CHANNEL



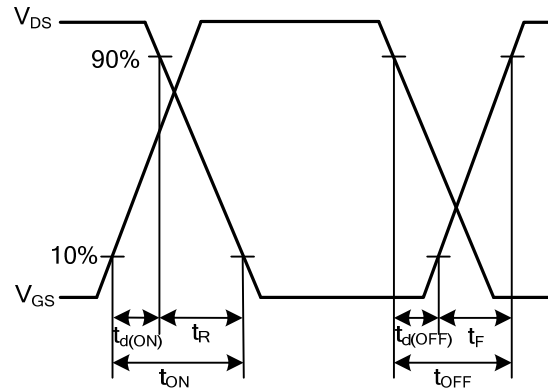
Gate Charge Test Circuit



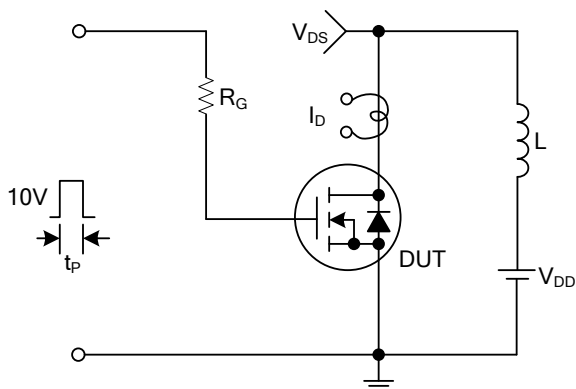
Gate Charge Waveforms



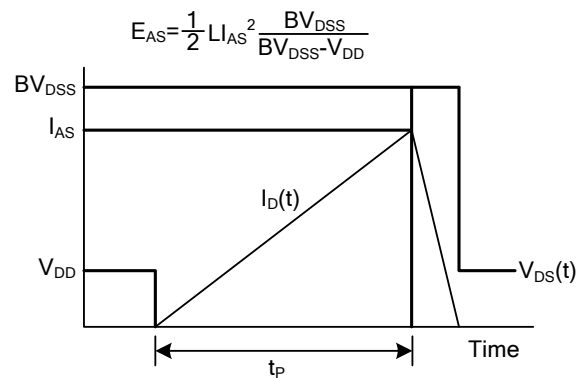
Resistive Switching Test Circuit



Resistive Switching Waveforms



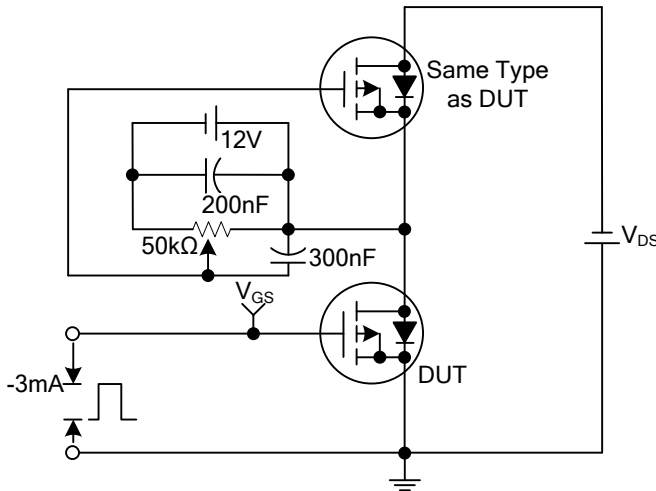
Unclamped Inductive Switching Test Circuit



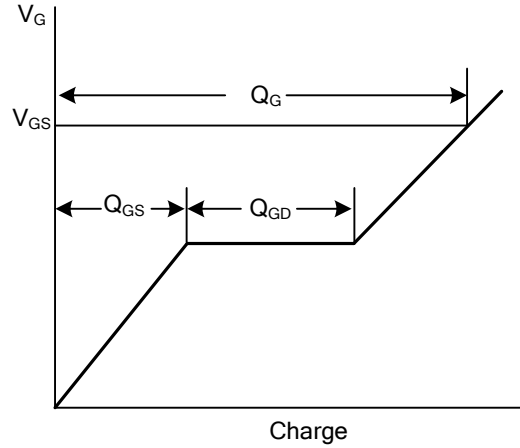
Unclamped Inductive Switching Waveforms

TEST CIRCUITS AND WAVEFORMS (Cont.)

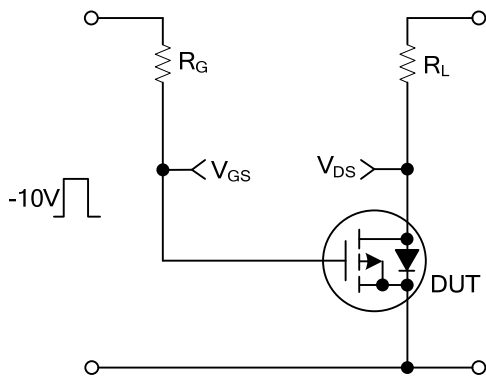
P-CHANNEL



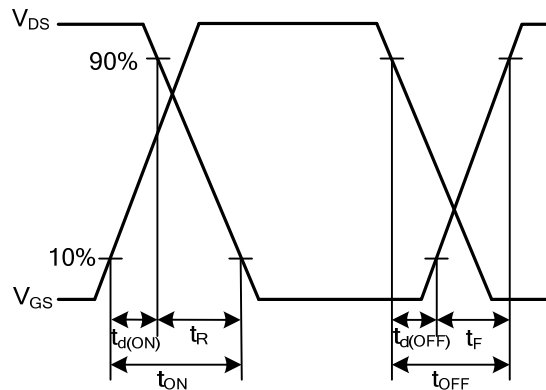
Gate Charge Test Circuit



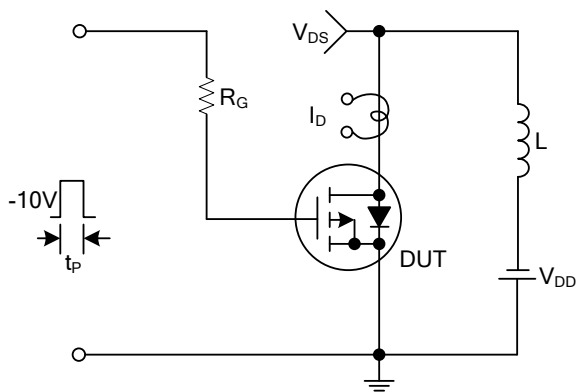
Gate Charge Waveforms



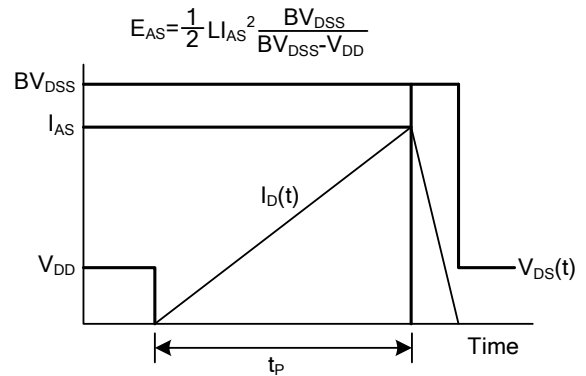
Resistive Switching Test Circuit



Resistive Switching Waveforms



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms



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